

SMR/1238-20

ADRIATICO RESEARCH CONFERENCE on
LASERS IN SURFACE SCIENCE

11–15 September 2000

Miramare – Trieste, Italy

*Lifetimes of conduction bands and surface states
at semiconductor surfaces*

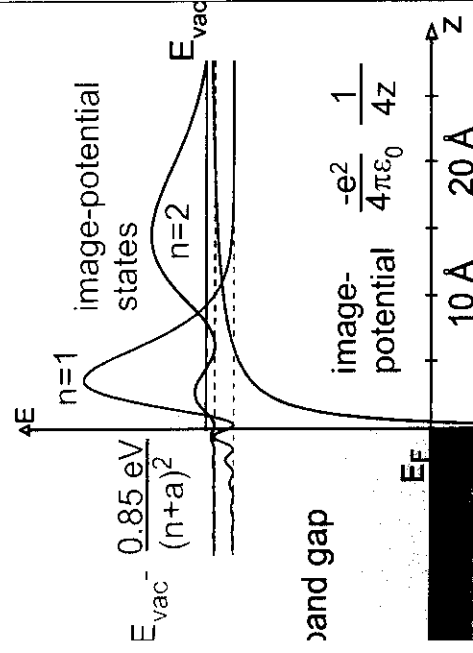
M. Weinelt
Universitat Erlangen
Erlangen, Germany

Lasers in Surface Science, Trieste 11. -15. 09. 2000

Th. Fauster, M. Weinelt, I. L. Shumay,
M. Kutschera, C. Kentsch, Ch. Reuß, K. Boger, M. Wiets, M. Roth

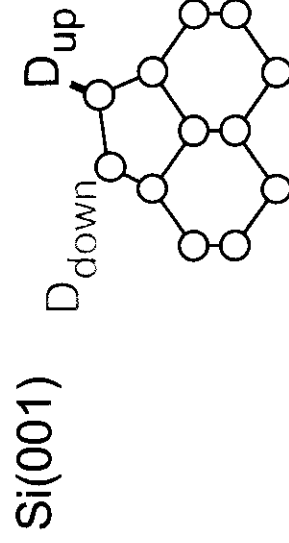
Lehrstuhl für Festkörperphysik, Universität Erlangen, Germany

Dephasing and energy
relaxation
of image-potential states



- confinement of electrons
- quantum-phase decay

Lifetimes of conduction bands
and surface states
at semiconductor surfaces

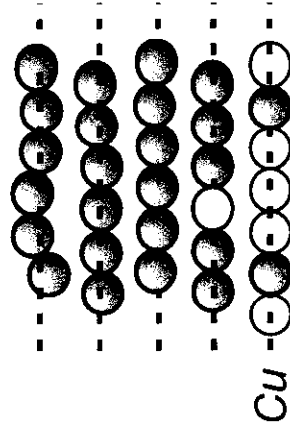


4H - SiC(0001)

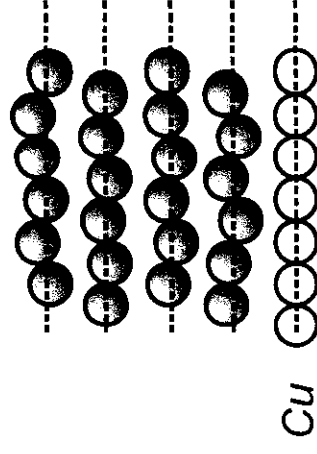
- electron & hole dynamics
- electronic structure

Pulsed Laser Deposition
growth of metal layers -
4 ML Fe/Cu(001)

PLD



TD

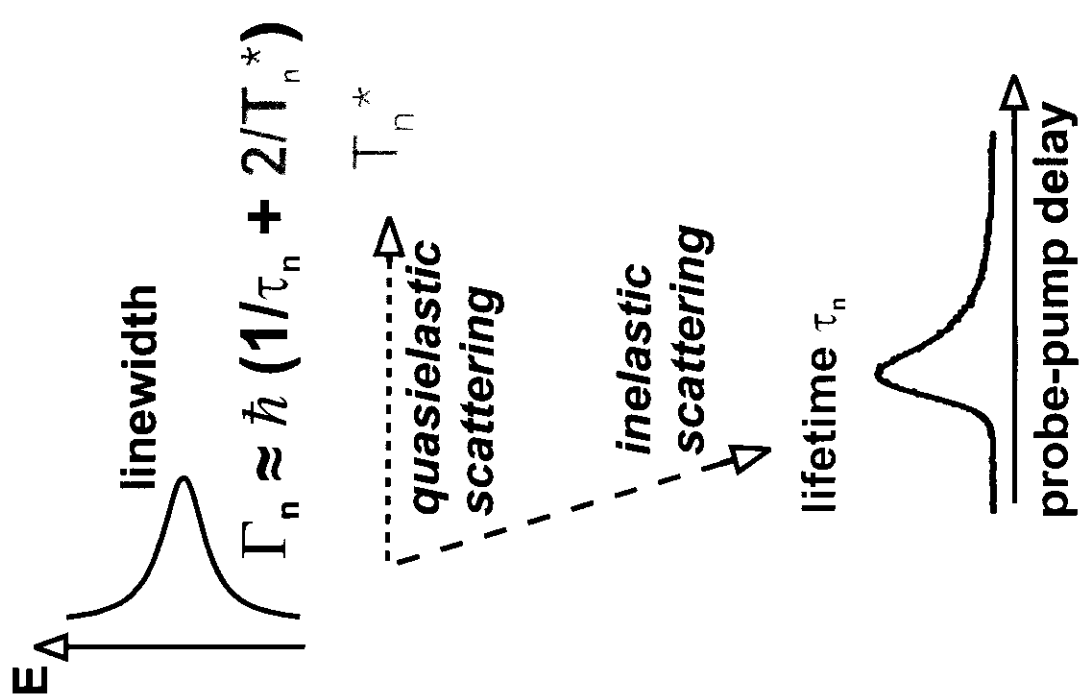


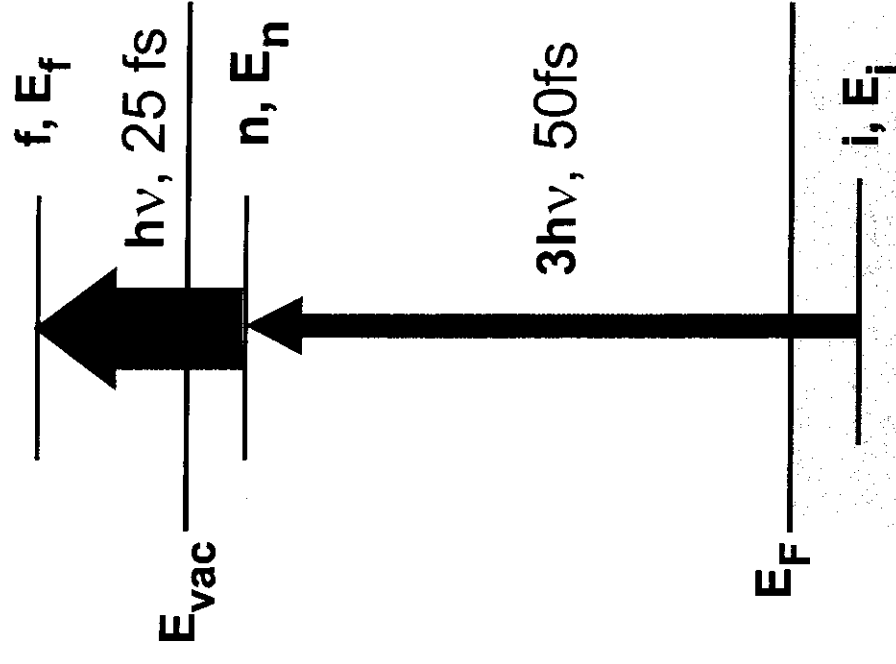
H. Jenniches et al. PRB 59(1999)1196

Outline

- Introduction, time-resolved two-photon photoemission (2ppe)
- Linewidth analysis
- 4H - SiC(0001)
Mott-Hubbard splitting of dangling-bond states
- Si(001)
 π and π^* - dangling bond states
electron dynamics and recombination

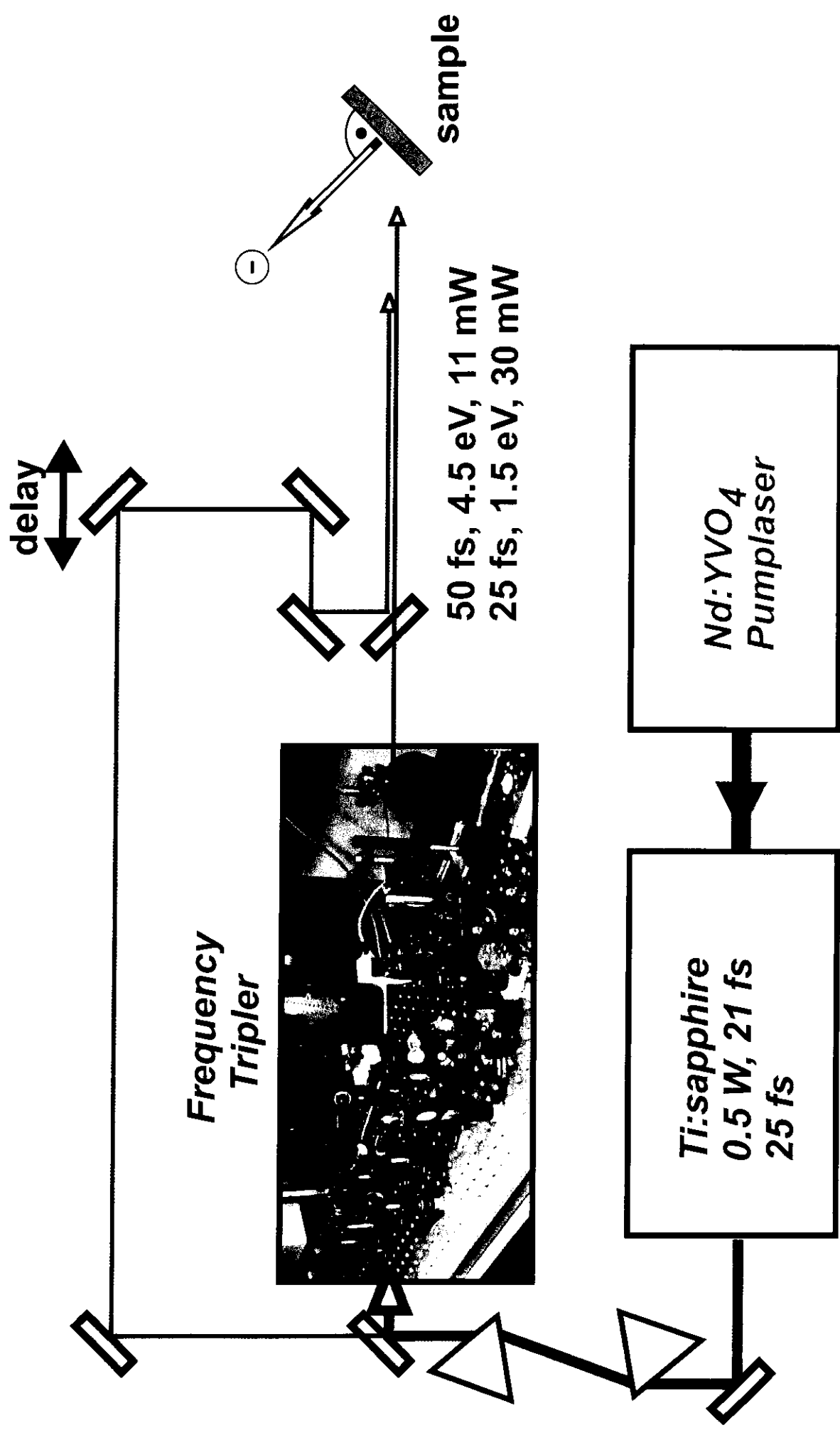
Energy and phase relaxation (decay and dephasing)





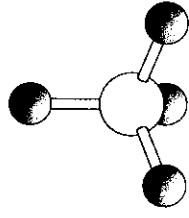
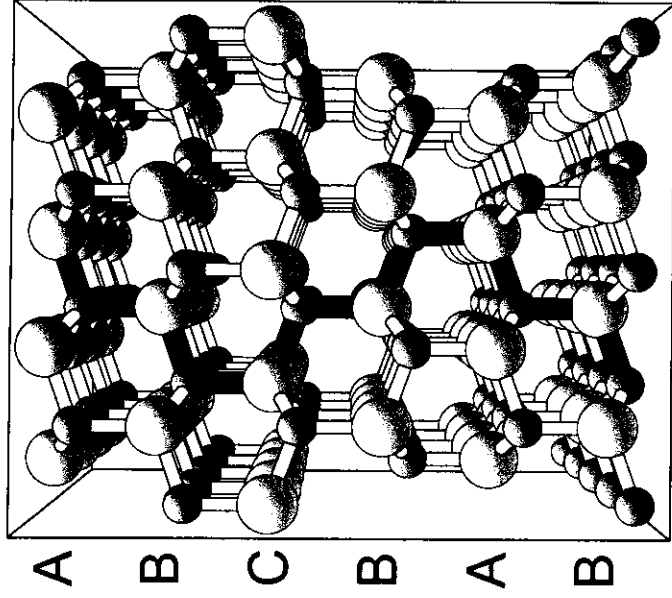
Two-photon photoemission

Experiment



Kristallstruktur von 4H-SiC(0001)

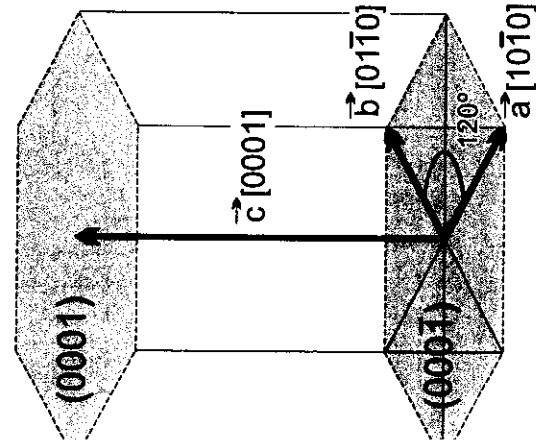
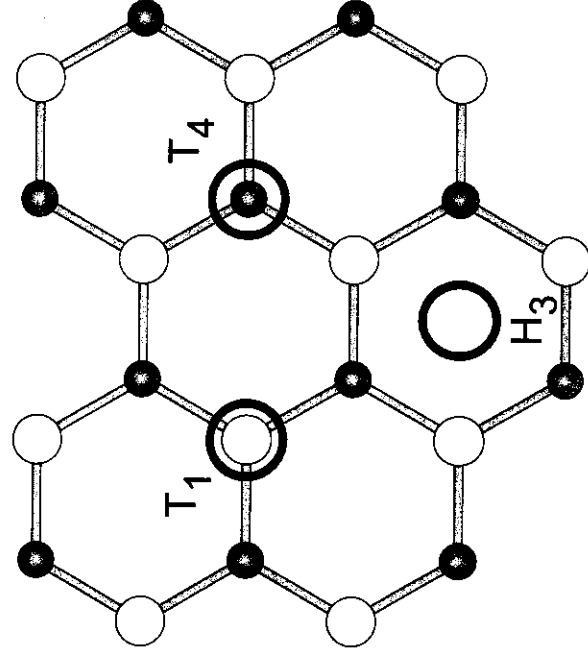
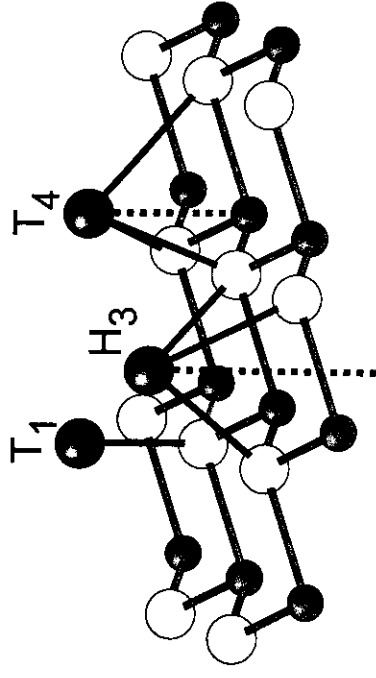
Oberfläche von Siliziumkarbid



○ Si

● C

● Si-Adatom



Polarität:

$(0001) \leftrightarrow \text{Si-terminiert}$

$(000\bar{1}) \leftrightarrow \text{C-terminiert}$

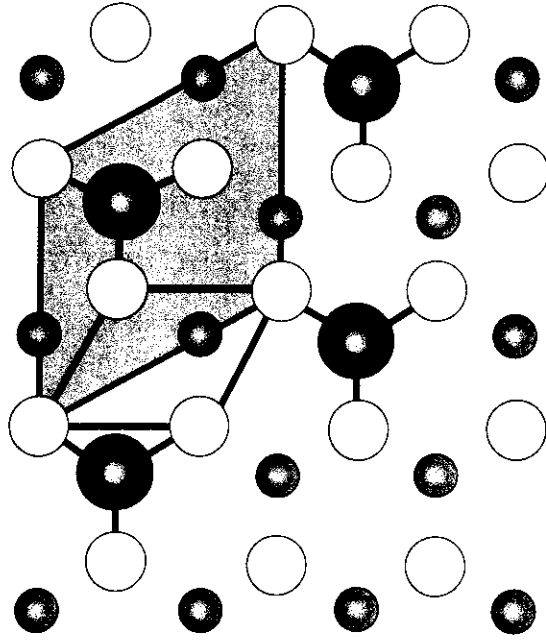
T₁ → 1-fach koord.
T₄ → 4-fach koord.
H₃ → 3-fach koord.

'Top'-Position der 1. atomaren Lage
'Top'-Position der 2. atomaren Lage
'Hollow'-Position der 1. Bilage

Warum 4H-SiC(0001)($\sqrt{3}\times\sqrt{3}$)R30° ?

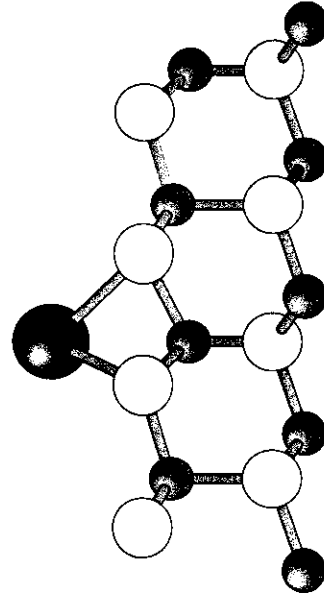
Si-Adatom auf T₄

Starke et al.,
Phys. Rev. Lett. 82 (1999) 2107



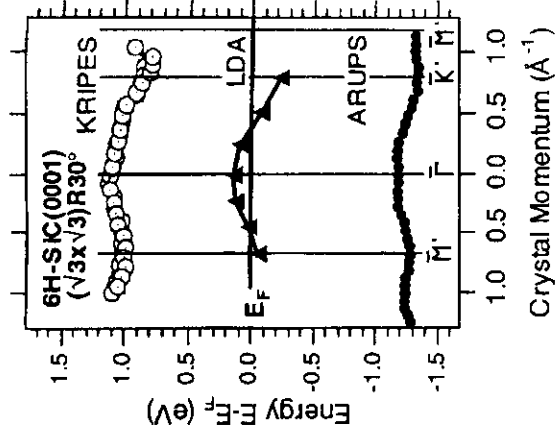
Aufsicht

Si-Adatom
Si
C



Seitenansicht

Diskrepanz: Theorie ↔ Experiment

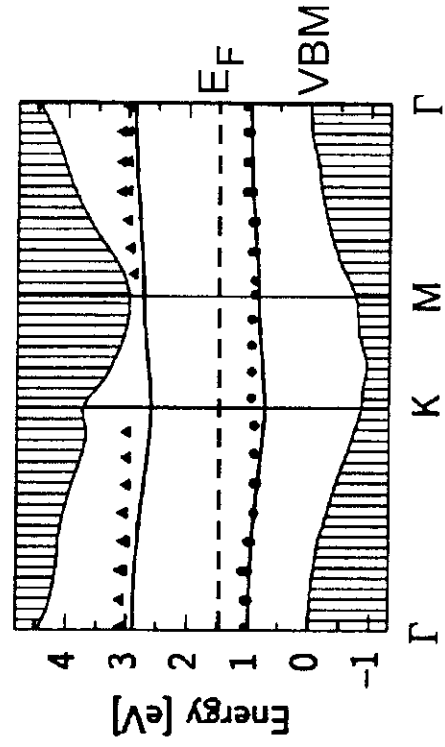


Themlin et al., Europhys.
Lett. 39 (1997) 61

Erklärung: Mott-Hubbard-Aufspaltung

Rohlfing, Pollmann, Phys.
Rev. Lett. 84 (2000) 135

6H-SiC(0001)-($\sqrt{3}\times\sqrt{3}$)R30°



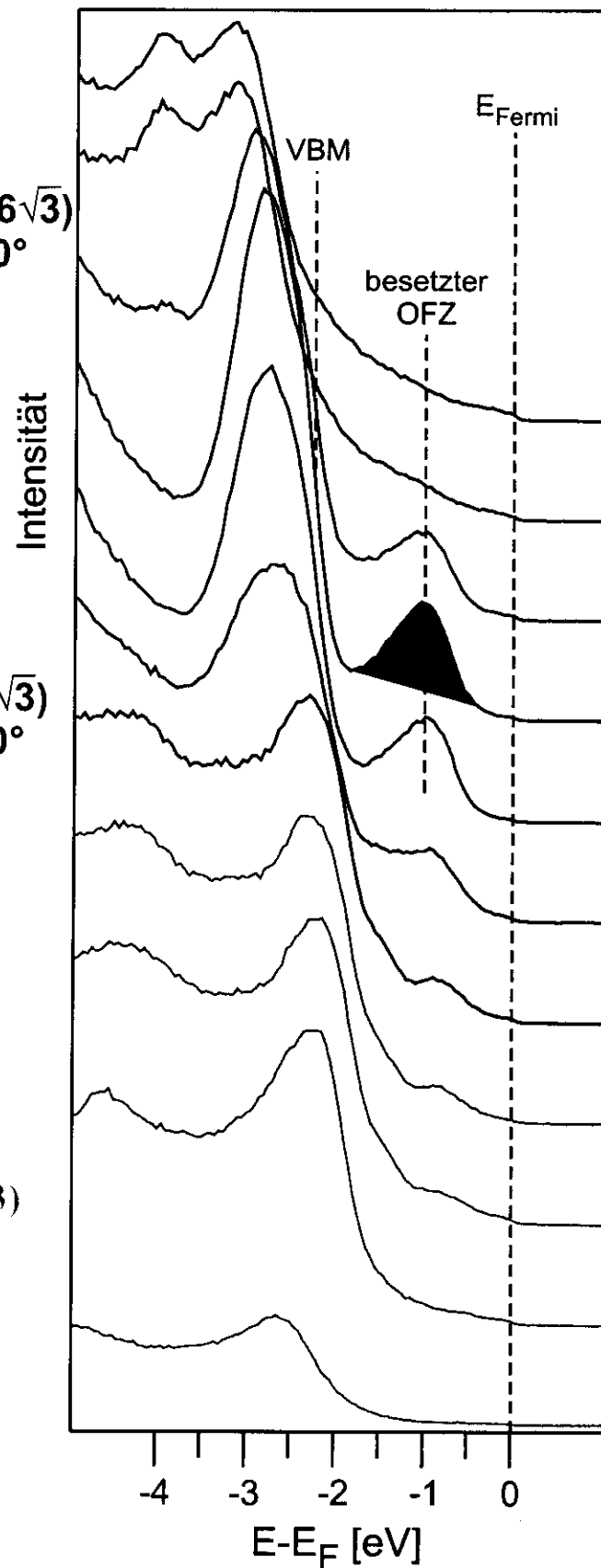
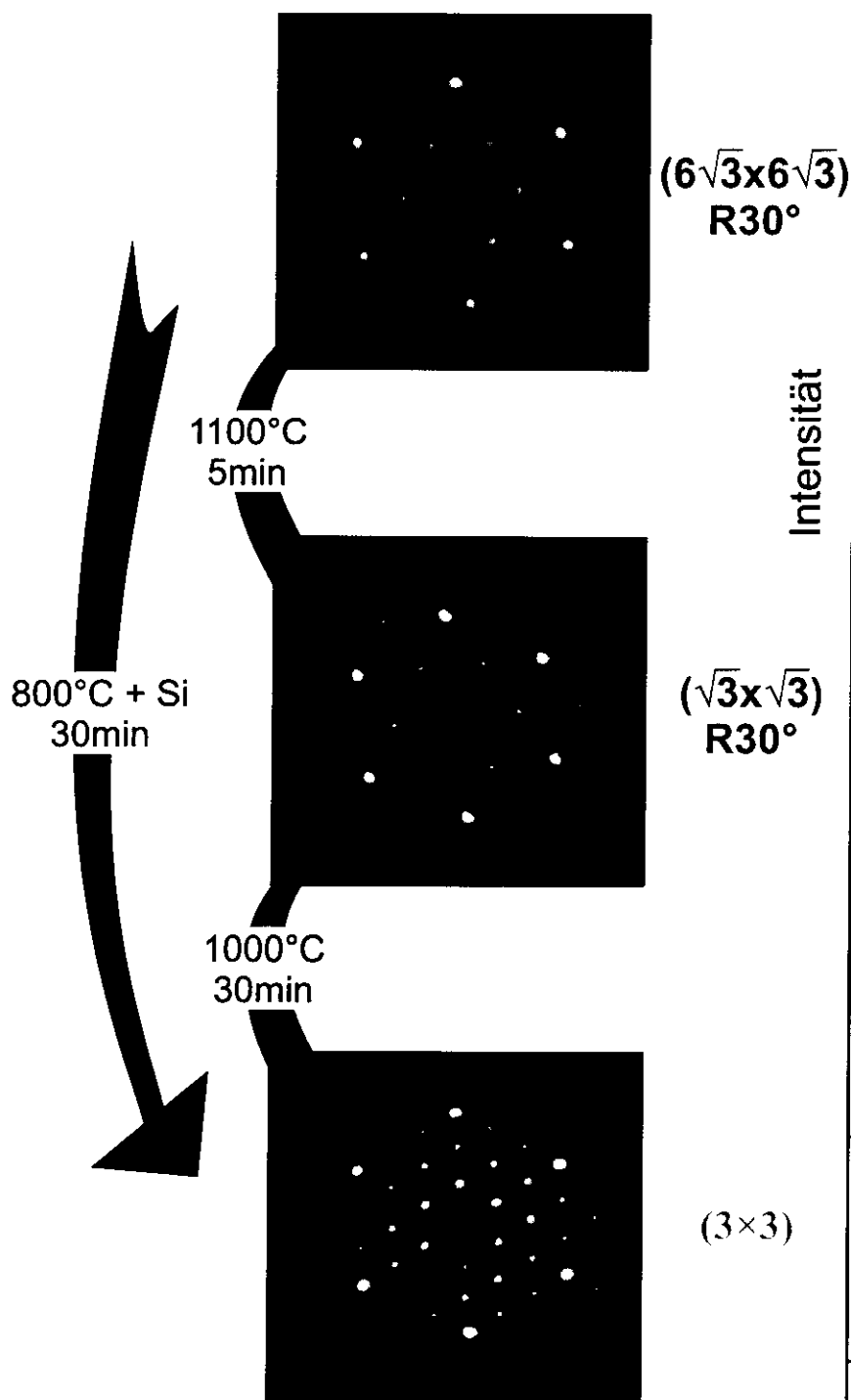
→ 'Reduktion der dangling bonds von 3 auf 1'

Rekonstruktionsphasen auf 4H-SiC(0001)

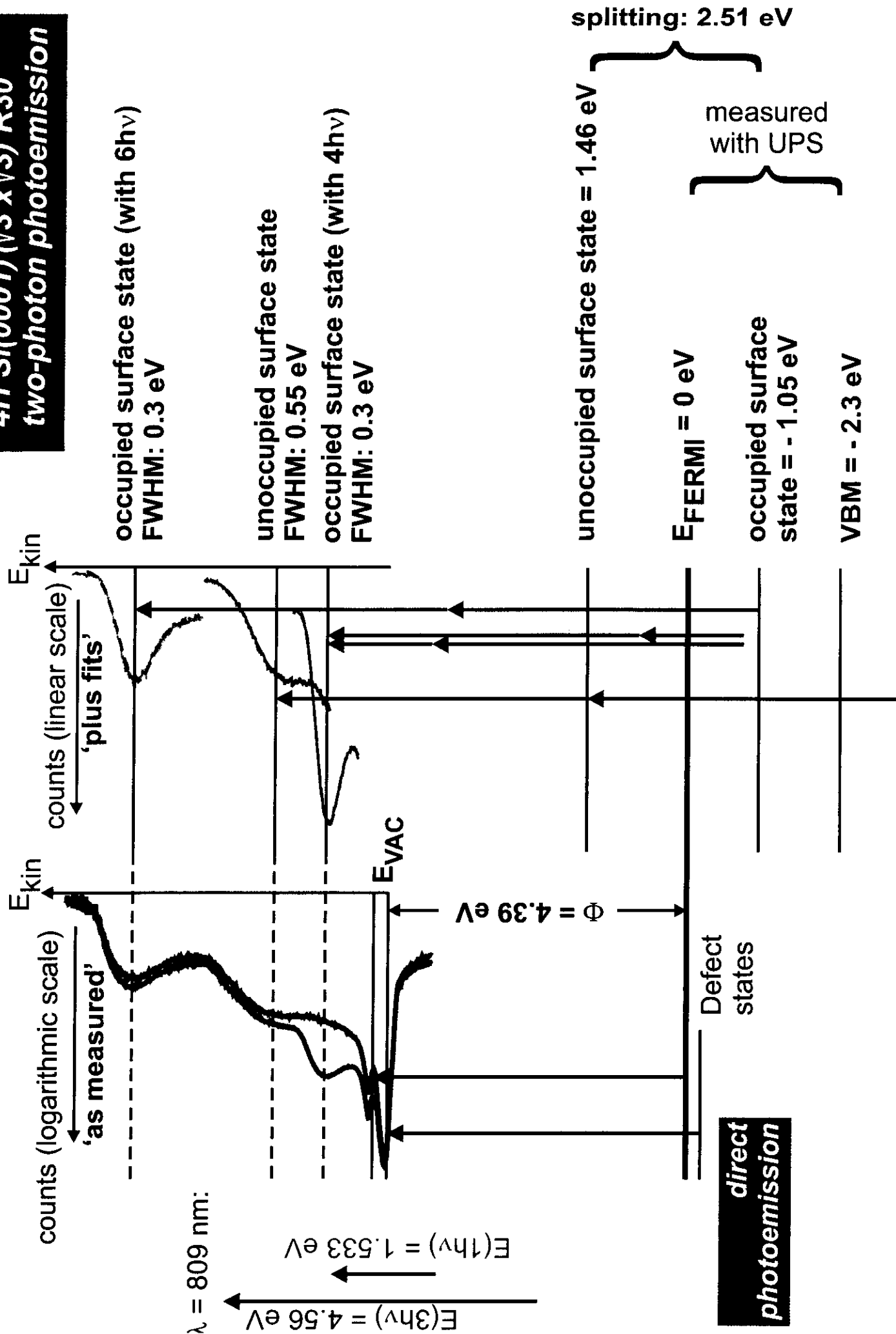
Präparation

LEED

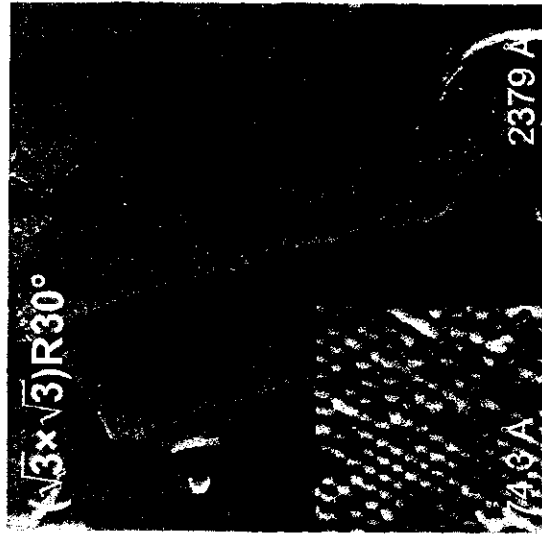
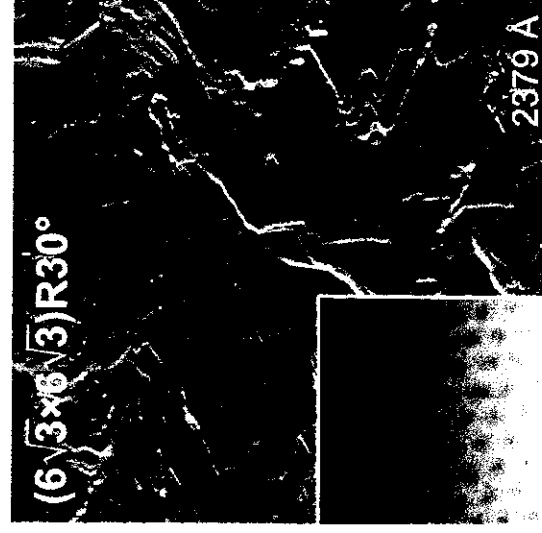
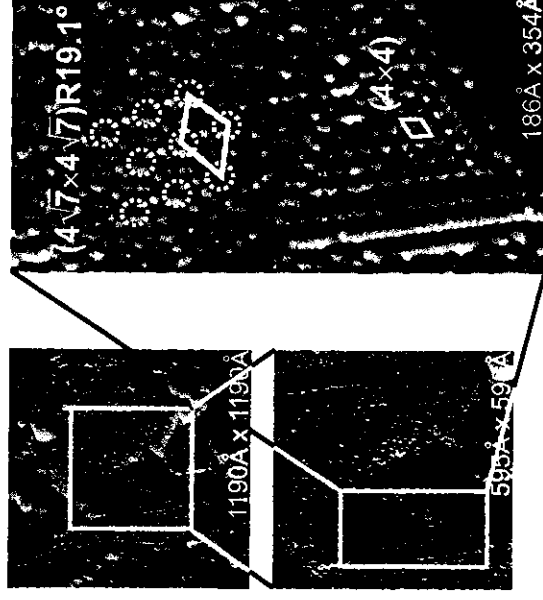
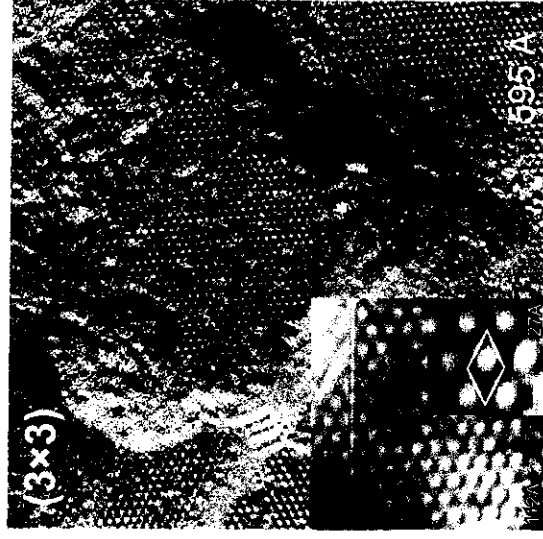
UPS



**4H Si(0001) ($\sqrt{3} \times \sqrt{3}$) R30°
two-photon photoemission**

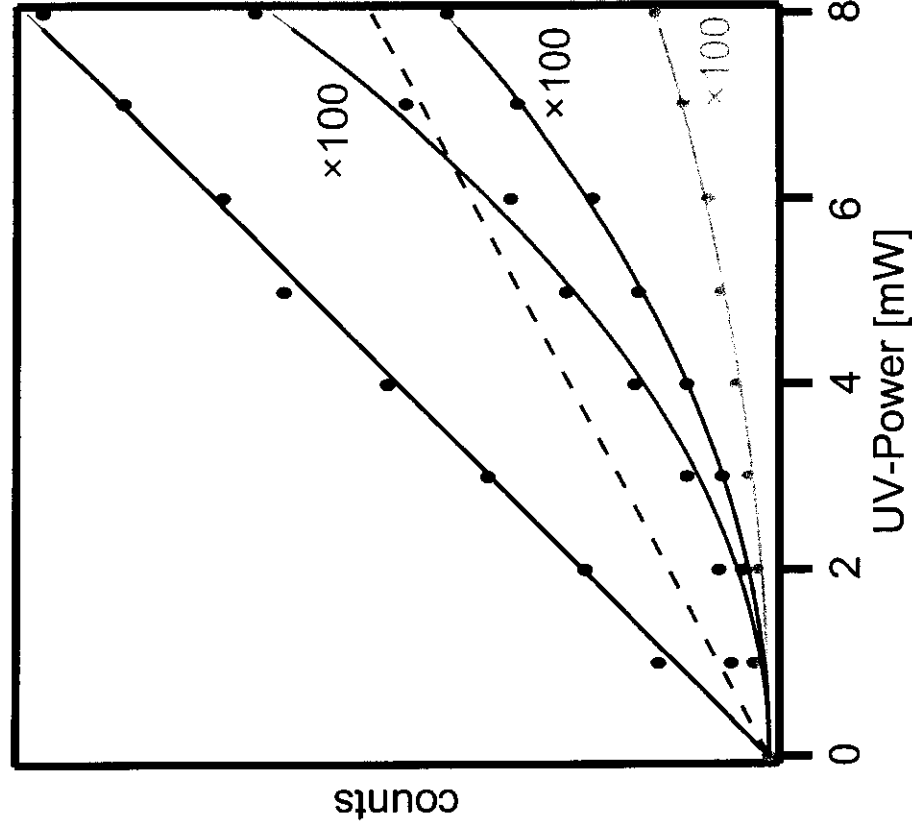
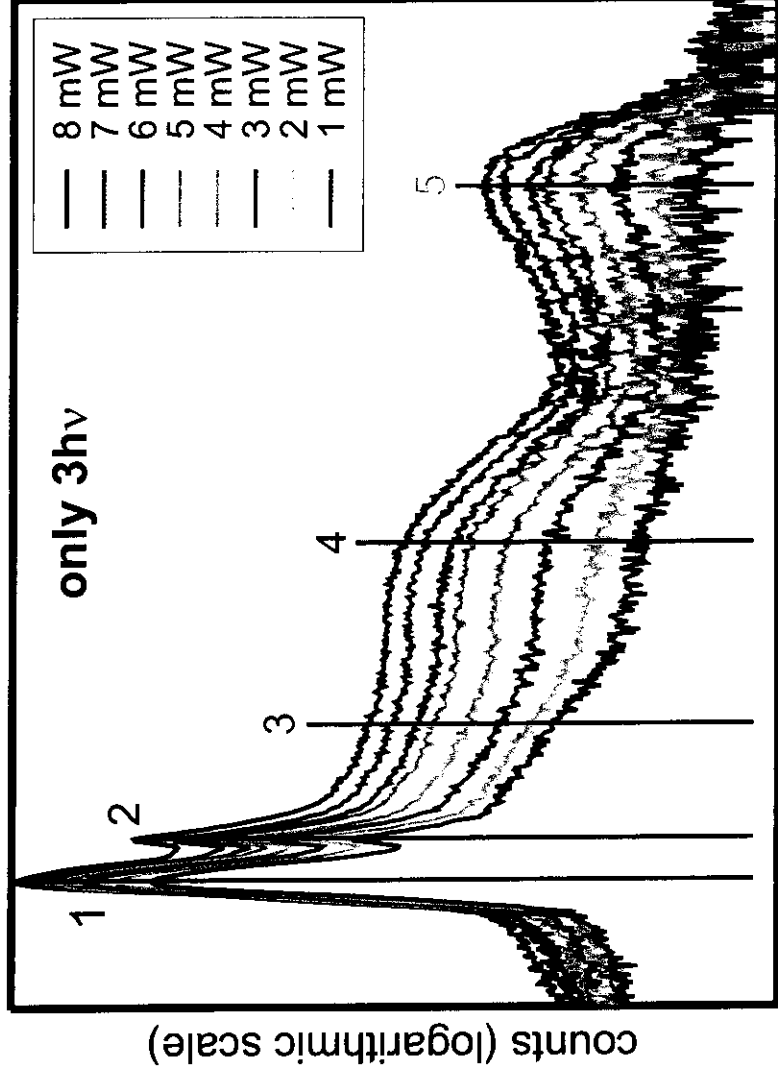


STM snapshots of SiC(0001) surface phases



annealing/
Silicon depletion

Dependence on UV power



Peak 1: linear with UV power $\Rightarrow$ 1PPE

Peak 3: quadratic with UV power $\Rightarrow$ 36 % 2PPE

Peak 3: linear with UV power $\Rightarrow$ 64 % 1PPE

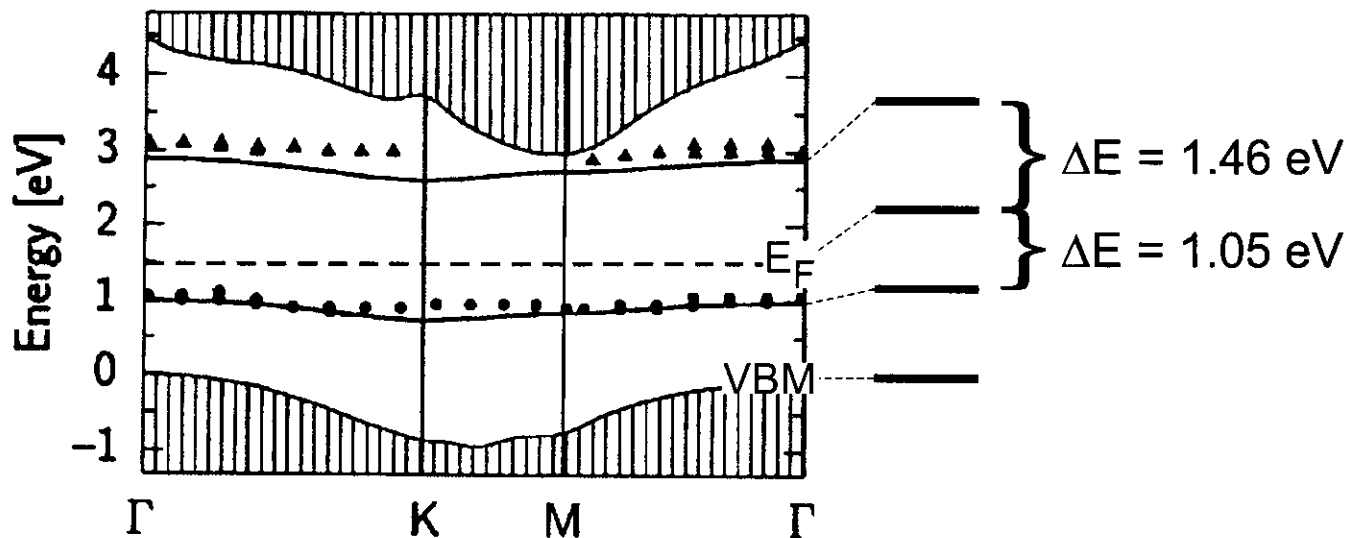
Contribution of Peak 2?

Peak 4: quadratic with UV power $\Rightarrow$ 2PPE

Peak 5: quadratic with UV power $\Rightarrow$ 2PPE

⇒ asymmetric splitting

Rohlfing, Pollmann, Phys.
Rev. Lett. **84**, 135 (2000)



calculation done for 6H-SiC(0001)-($\sqrt{3} \times \sqrt{3}$)R30° !
4H-SiC(0001): larger splitting (due to a larger bulk band gap)

Conclusions

4H-SiC(0001)-($\sqrt{3} \times \sqrt{3}$)R30°:

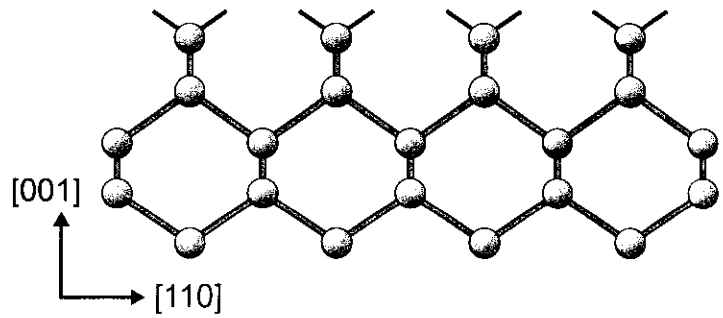
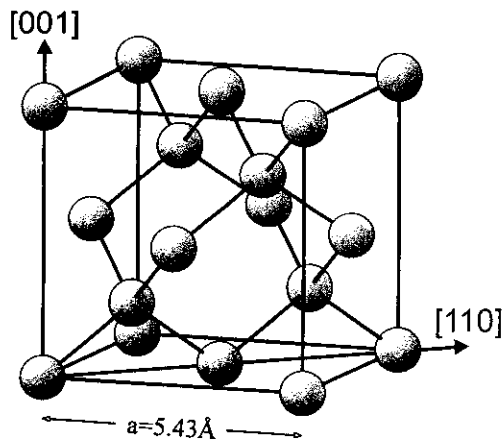
The **occupied** and the **unoccupied** surface state can be observed with **2PPE simultaneously** in **one** experiment.

The proposed **asymmetric splitting** can be confirmed: $\Delta E = 2.51$ eV.
→ Occupied surface state $\leftrightarrow E_{\text{FERMI}}$: $1.05 \text{ eV} \pm 0.02 \text{ eV}$
→ Unoccupied surface state $\leftrightarrow E_{\text{FERMI}}$: $1.46 \text{ eV} \pm 0.02 \text{ eV}$

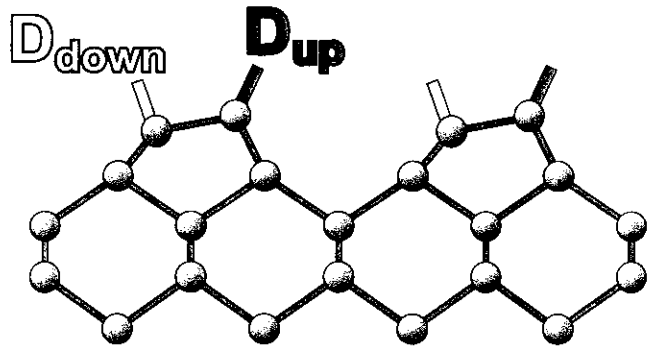
6H-SiC(0001)-($\sqrt{3} \times \sqrt{3}$)R30°:

A **smaller splitting** can be observed: $\Delta E = 2.34$ eV.
This can occur due to the smaller bulk band gap.

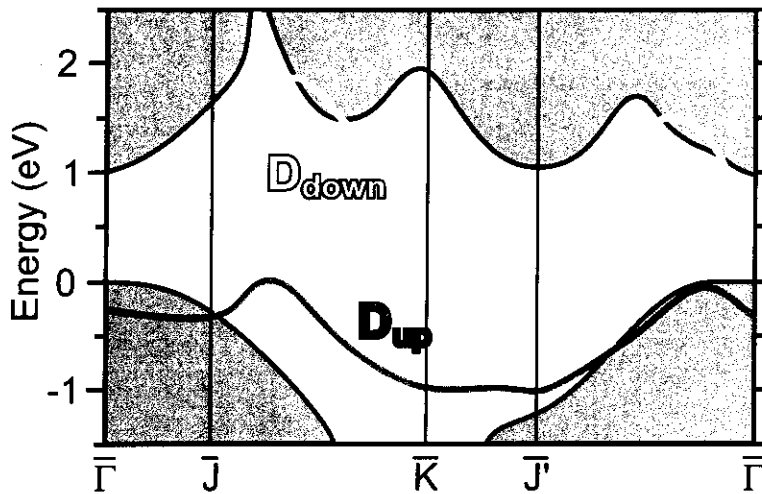
Si(001): Geometric structure



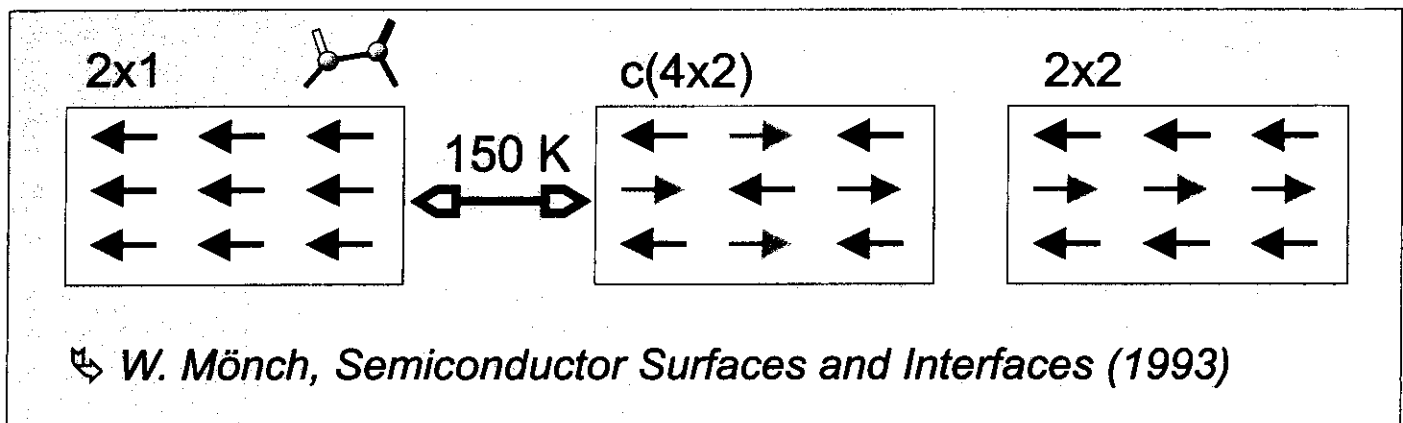
Surface reconstruction
Si(001) 2×1 :



Asymmetric Dimers $\Rightarrow$ occupied D_{up} & unoccupied D_{down} surface band

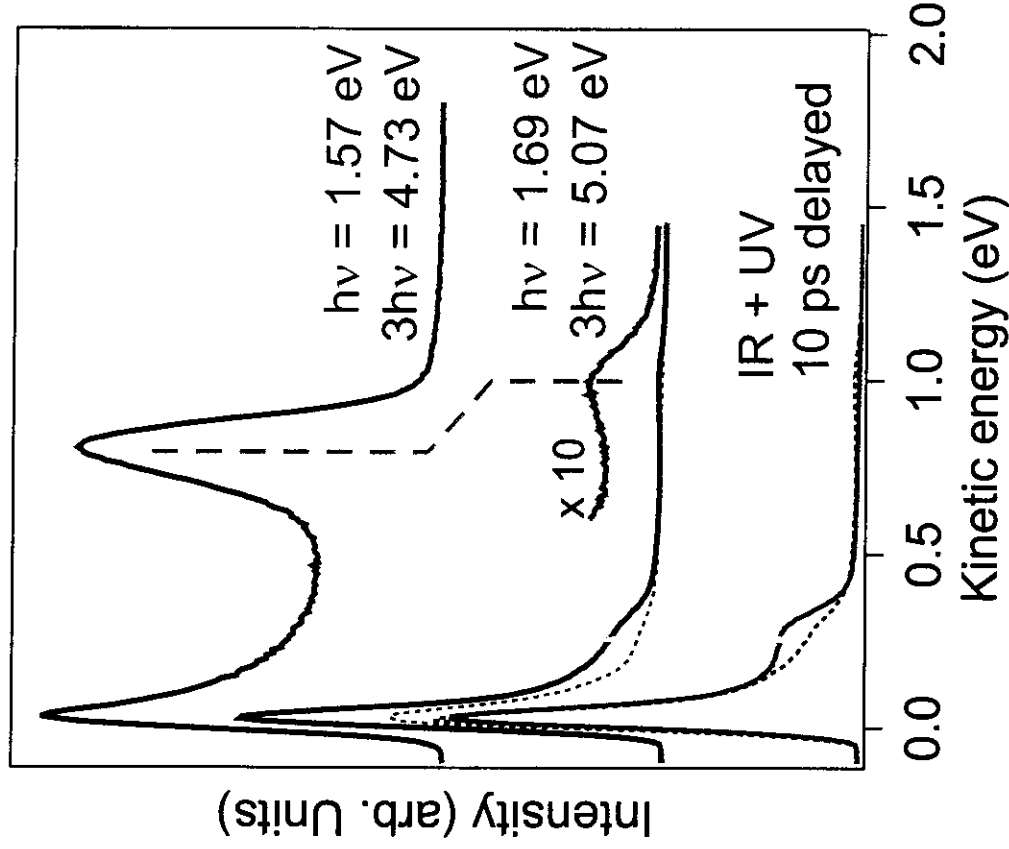


J. Pollmann et al., Appl. Surf. Sci. **104/105**, 1 (1996)

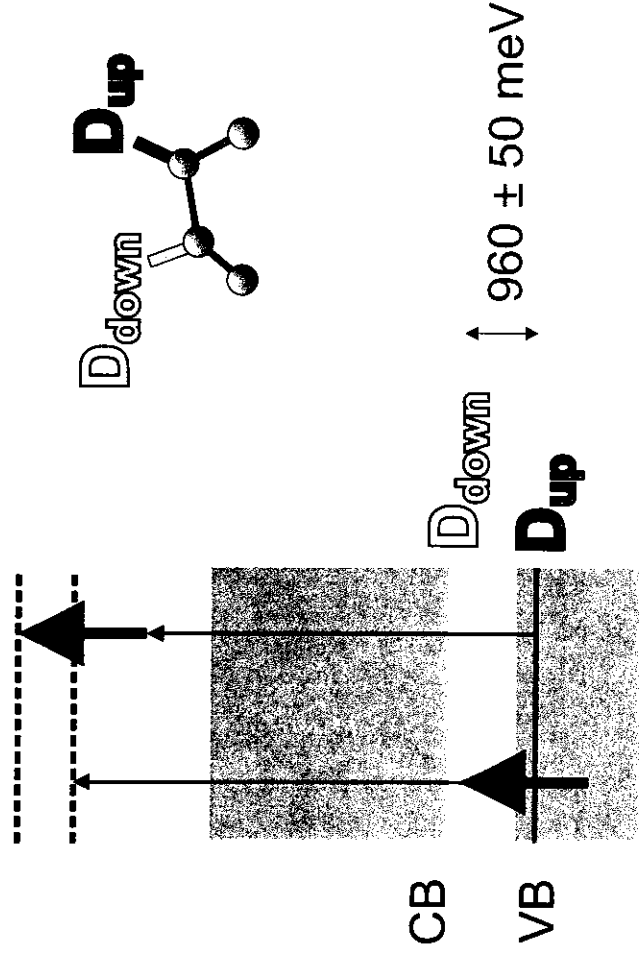


Si(001) Two-photon photoemission

Si(001) (2x1), T = 300 K



➔ IR + UV excitation of occupied D_{up}



energy relative to valence-band maximum:

$D_{up} = -260$ meV

$D_{down} = 700$ meV

good agreement with UPS (1), IPS (2) and GWA calculations (3)

(1) R. I. G. Uhrberg, PRB 24 (1981) 4684.

L. S. O. Johansson PRB 42 (1990) 1305.

(2) J. E. Ortega and F. J. Himpsel, PRB 47 (1992) 2130

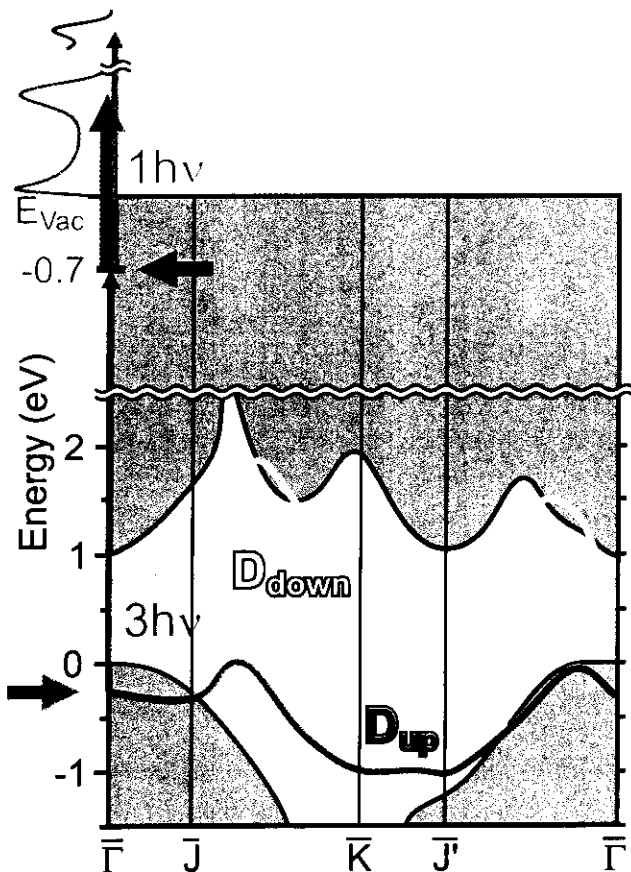
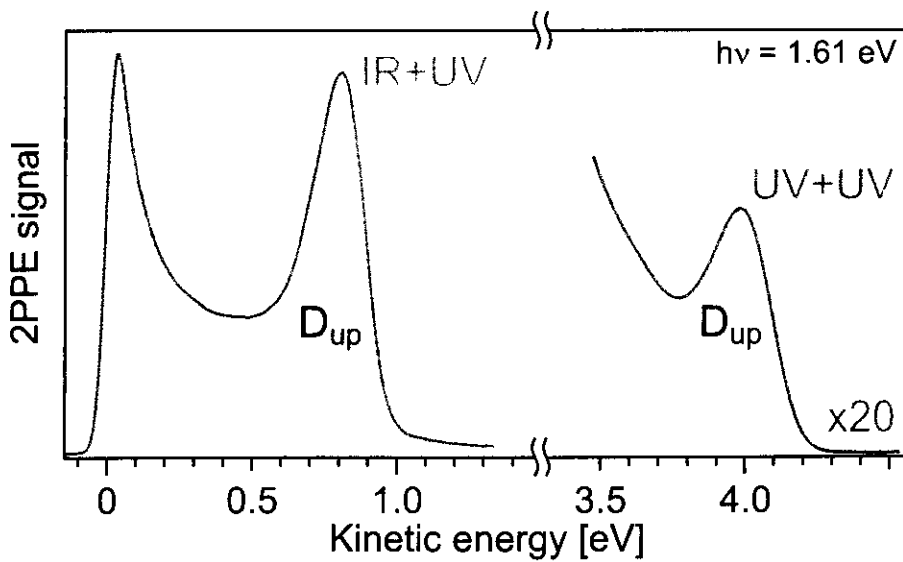
L. S. O. Johansson and B. Reihl,

Surf. Sci. 269/270 (1992) 810

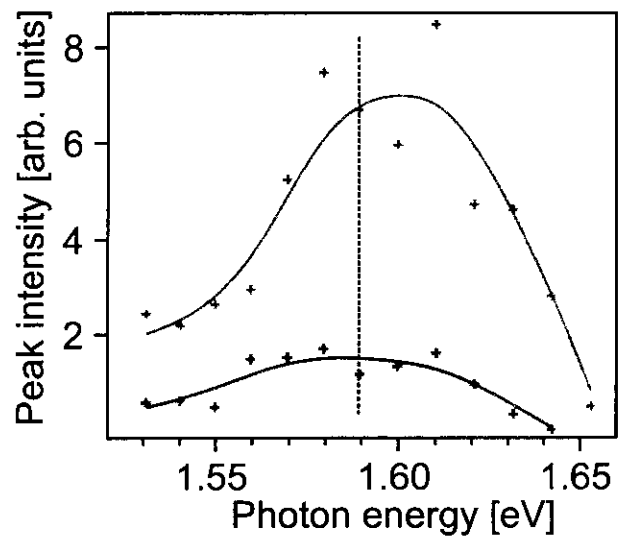
(3) J. Pollmann et al.,

Apl. Surf. Sci. 104/105(1996)1.

Si(001): Occupied D_{up} state



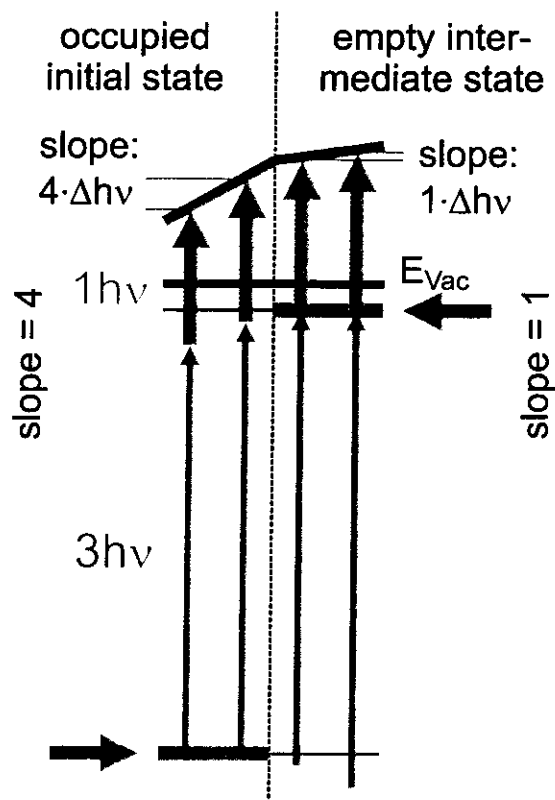
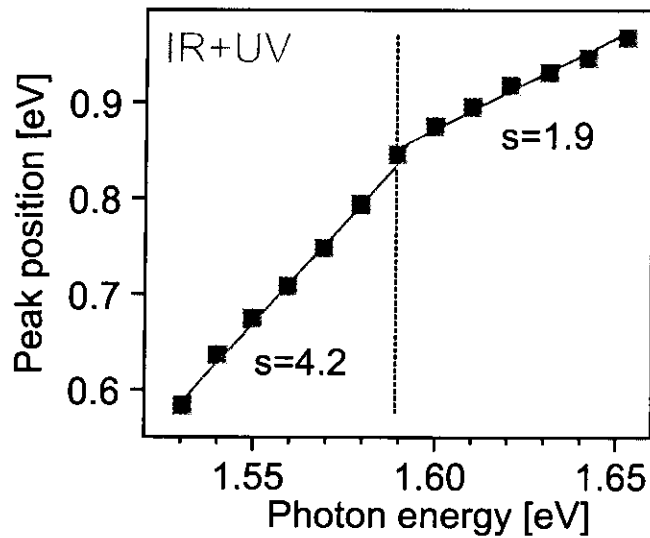
Resonance:



$\Rightarrow$ Occupied D_{up} SS

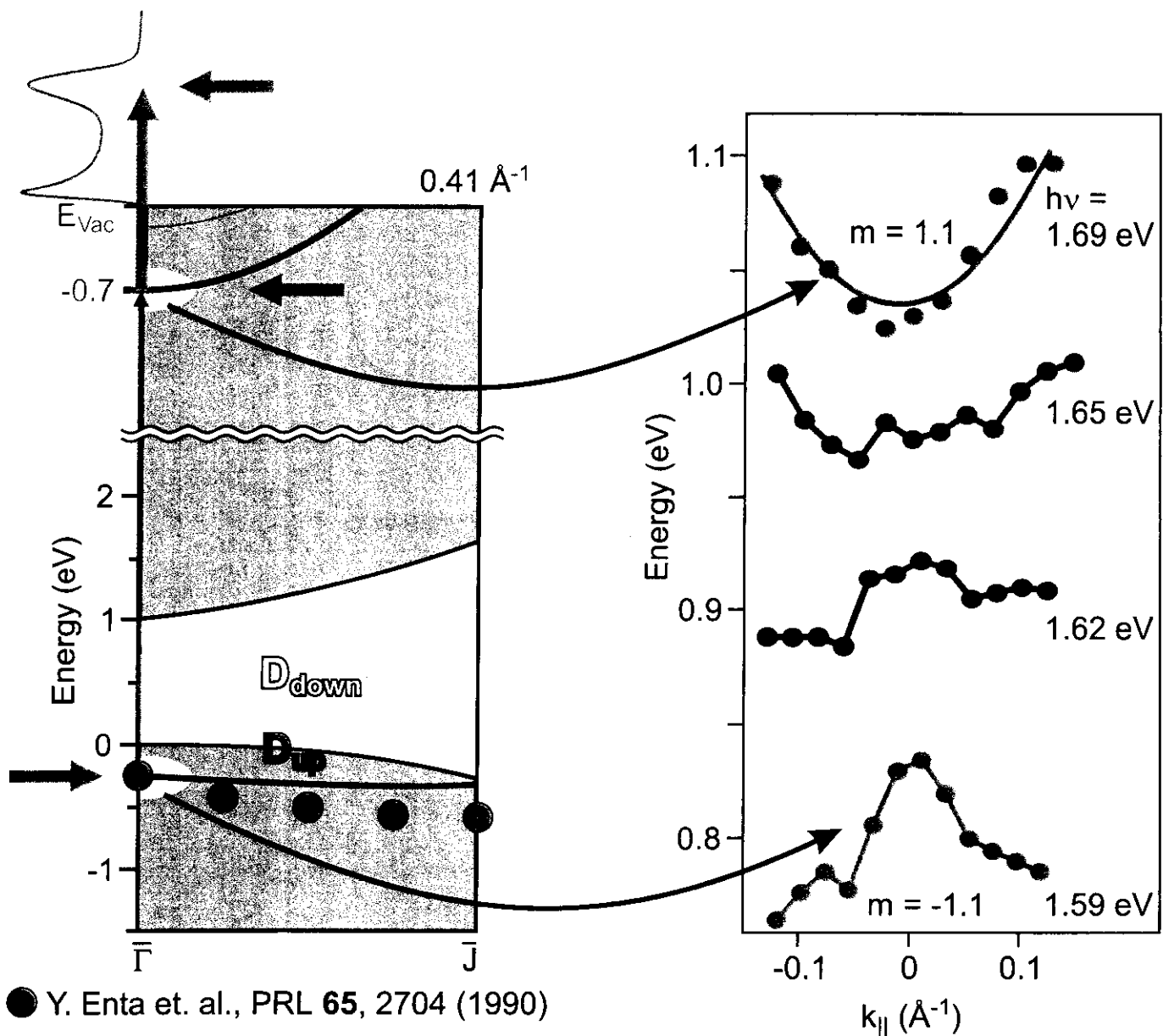
$\Rightarrow$ Resonance with unoccupied SS
approx. 0.7 eV below E_{Vac}

Si(001): Unoccupied state



⇒ Resonance between occupied (D_{up}) and unoccupied (0.7 eV below E_{vac}) surface state

Si(001): Dispersion & lifetime of the resonance



⇒ Is unoccupied SS an image-potential state?

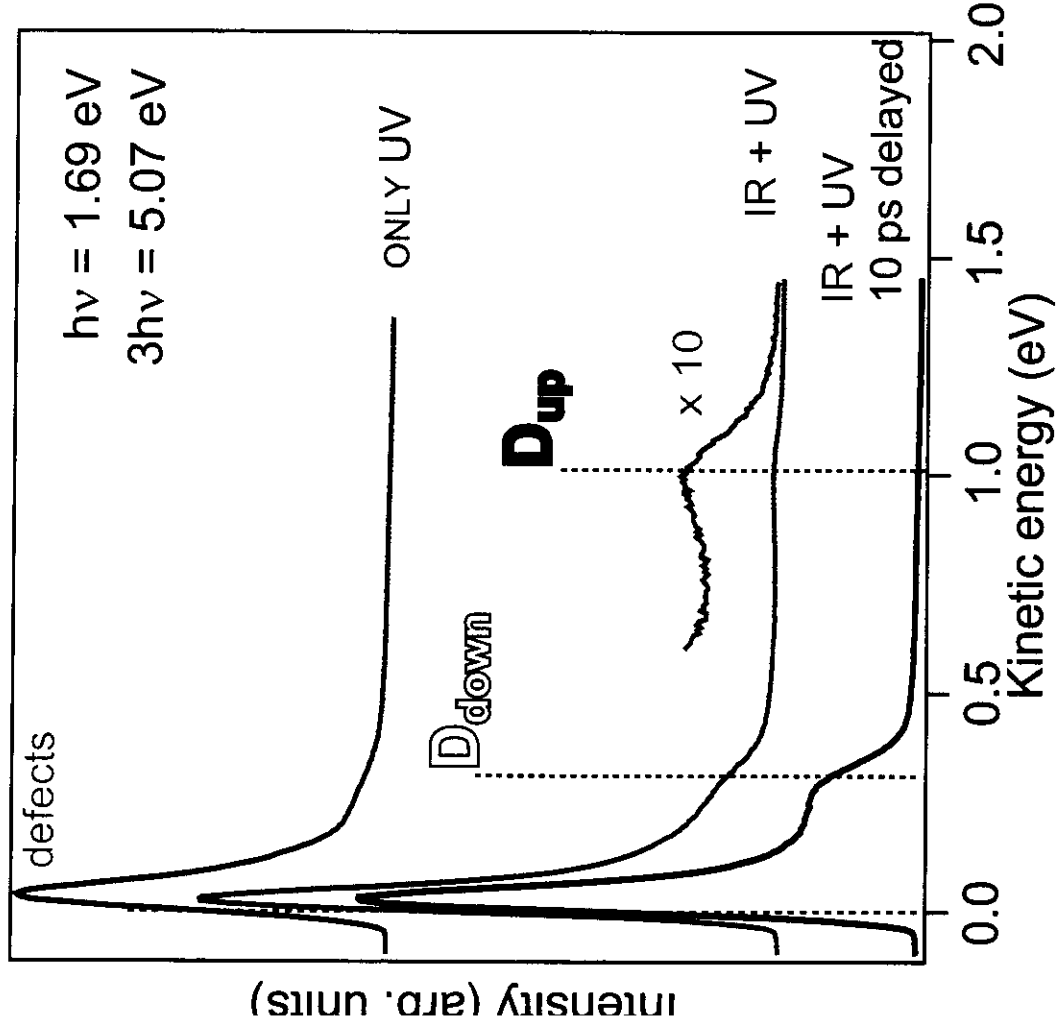
$\epsilon_{\text{surface}}(\text{Si } 001) = 12 \dots 13$

$$\rightarrow E_{\text{bind}} = \frac{0.85 \text{ eV}}{n^2} \cdot \left(\frac{\epsilon - 1}{\epsilon + 1} \right)^2 = 0.6 \text{ eV}$$

⇒ Lifetime of unoccupied state: $10 \pm 5 \text{ fs}$

Si(001) Two-photon photoemission

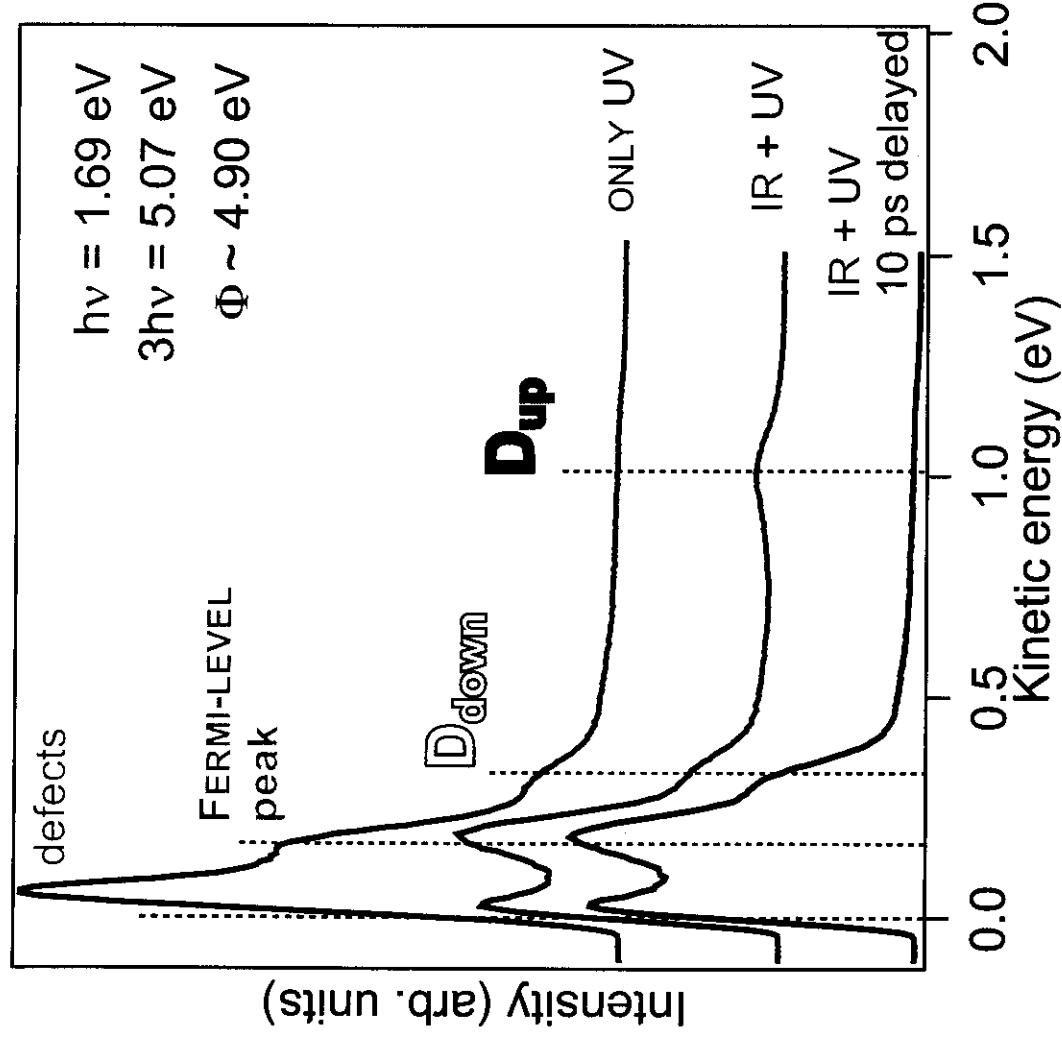
Si(001) (2x1), T = 300 K



- IR heating of direct photoemission
- "no" Fermi-level peak

IR + UV excitation of occupied D_{up}

Si(001) c(4x2), T = 150 K

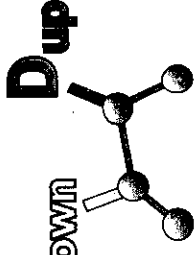


- IR depletion of defect states
- strong Fermi-level peak

Direct vs. two-photon photoemission

Si(001)

D_{down}



direct photoemission

$$E_{kin} = 3h\nu - \Phi$$

$$E_{vac}, E_{kin} = 0 \text{ eV}$$

1ppe ~ 1



3hν

E_F

————— CB

D_{down}

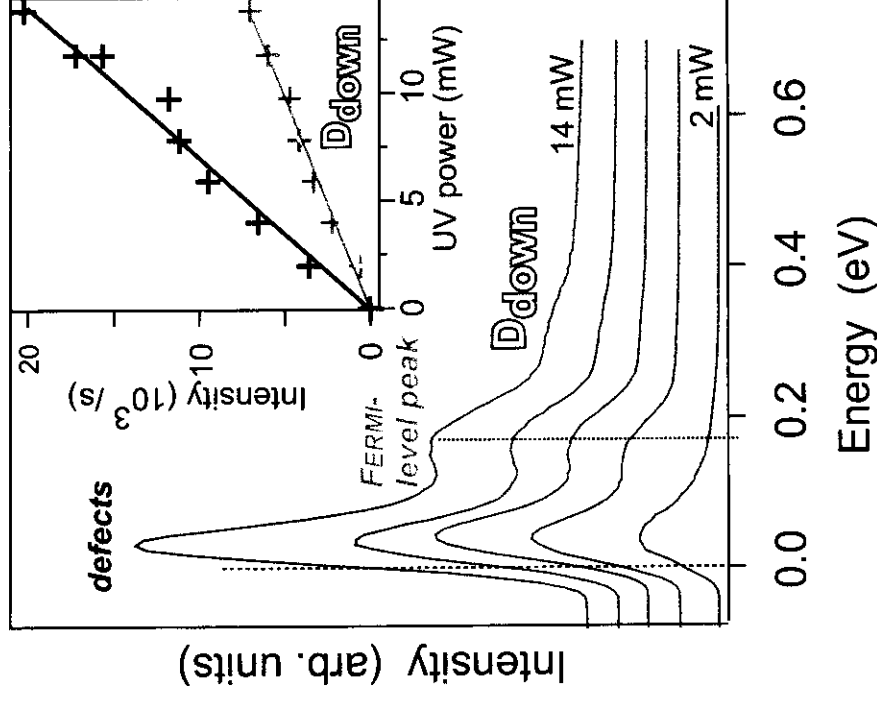
FERMI-Level

E_F

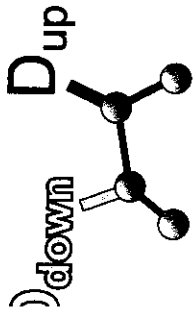
defects

————— VB

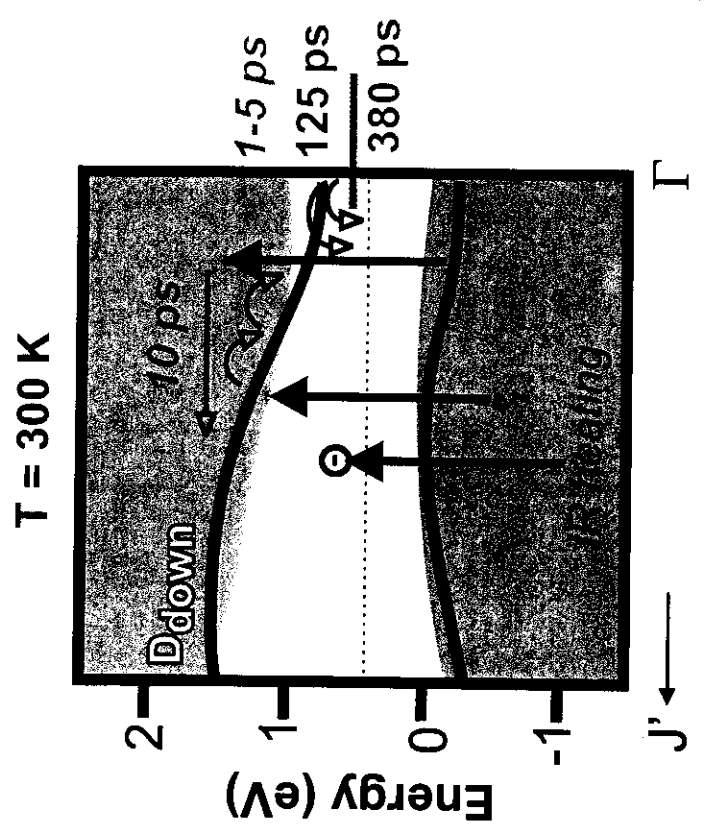
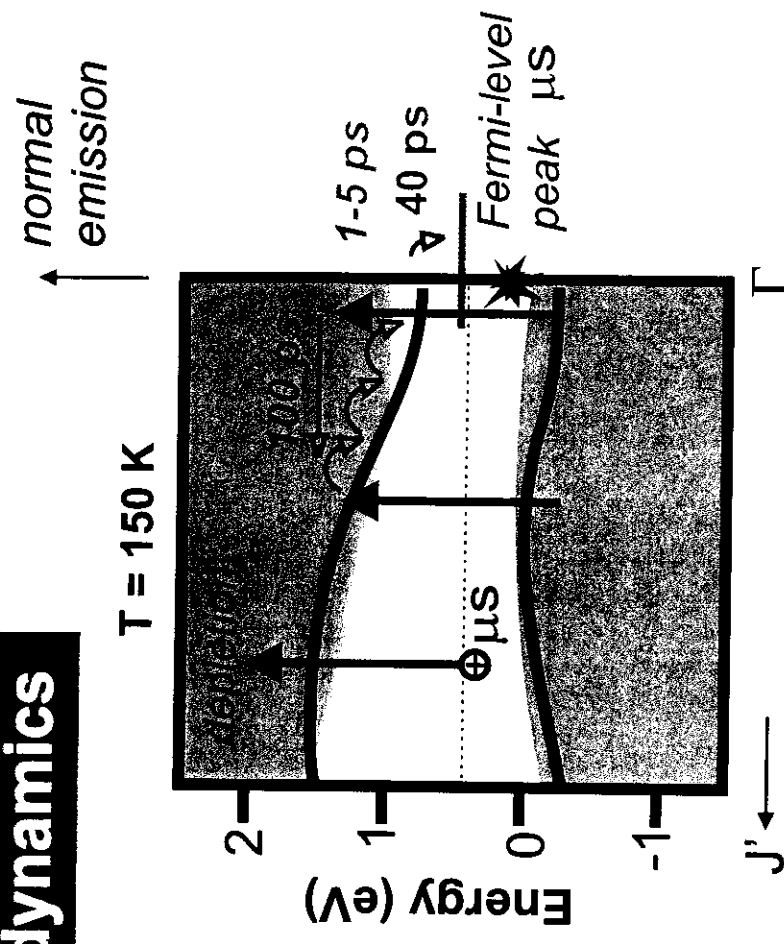
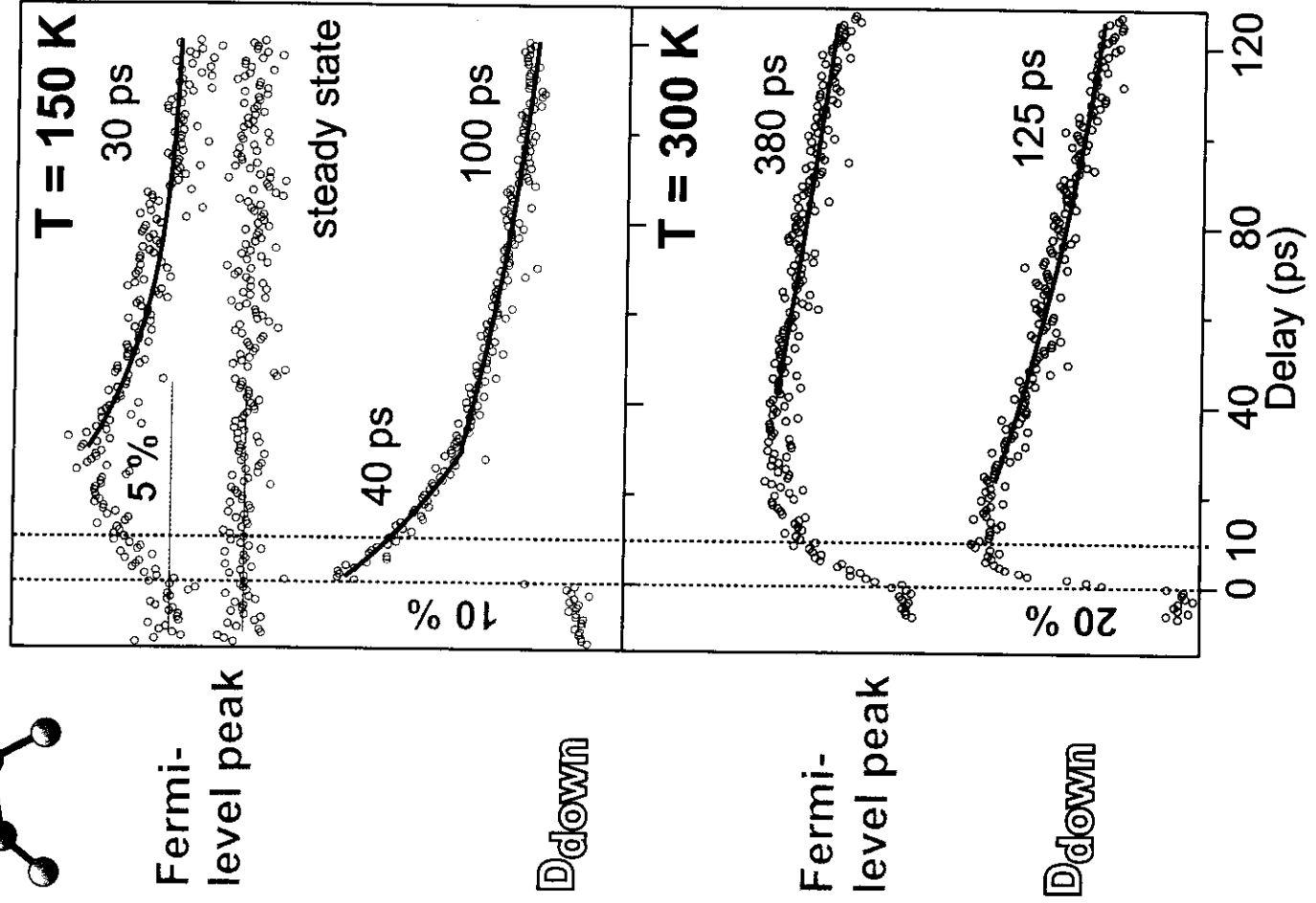
T = 120 K, c(4x2)



Fermi-level peak: direct photoemission
surface defects in band gap $\sim 10^{11}/\text{cm}^2$



Si(001) electron-hole dynamics

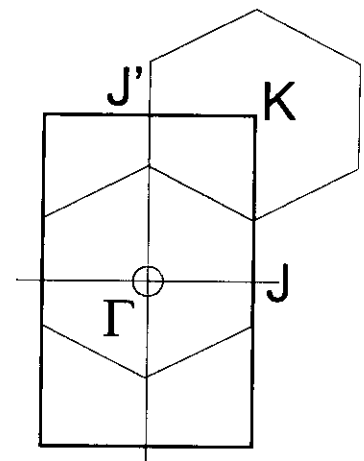
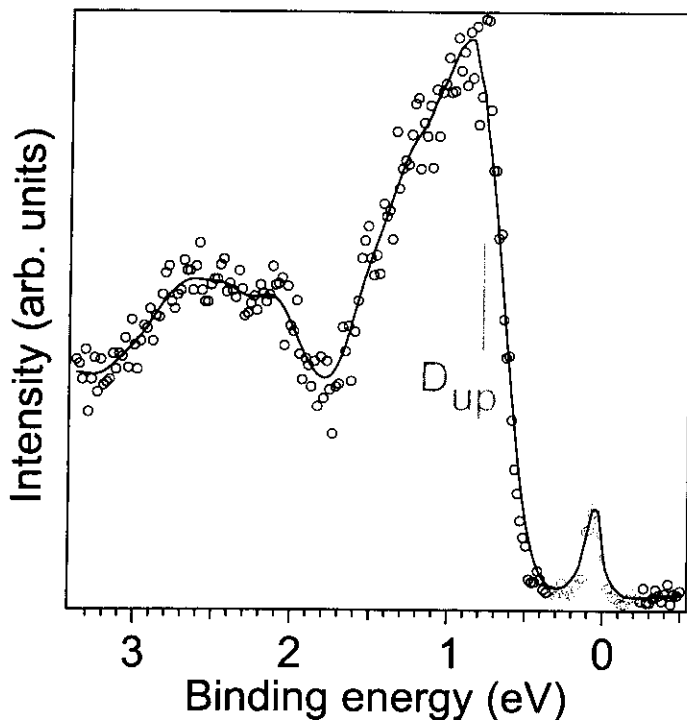


Si(001)

- D_{up}, D_{down} identified in two-photon photoemission
- Surface-state gap at $\bar{\Gamma}$: 960 ± 50 meV
- Electron & hole dynamics:
ps for T = 300K
 $\sim \mu\text{s}$ T = 150K

What is the Fermi-level peak?

(seen in UPS @ 120 K)



2ppe: energy 0.15 eV below D_{down}

Theory: D_{down} (2x1) vs. c(4x2): 0.35 eV (GWA) [1]
0..56 eV (LDA) [2]

[1] J. E. Northrup, *PRB* 47 (1993) 10032.

[2] P. Krüger, *priv. Commun.*

Conclusions

- Linewidth analysis (large delay)

$\sim \text{Im} \{ \text{Lorentzian}(\text{pure dephasing } 2\Gamma^*) \otimes$

$| \mathbf{F}[\text{pulse-envelope} \times \exp(-\Gamma/2 t)] |^2 \}$

- 4H - SiC(0001)

Mott-Hubbard splitting
of dangling-bond states is asymmetric
and dependent on band gap (6H)

lifetime measurements failed - defects ?

- Si(001)

π and π^* - dangling bond states
electron dynamics and recombination
Fermi-level peak ?

$T = 300 \text{ K}$

ps - time scale, phonon assisted recombination

$T = 150 \text{ K}$

μs - time scale, radiative recombination